AMENDMENTS TO THE SPECIFICATION:

Please replace the paragraph bridging page 3 and 4 with the following rewritten paragraph.

The present invention, which achieves above-mentioned objectives, comprises: a testing means, which tests LSI; a testing means, which tests said memory LSI; a data readout means, which reads data that is output ~~form~~ from said testing means and holds it in memory region of an analytical computer; an address difference calculation means, which calculates address differences between two defect data; an address difference histogram production means, which produces an address difference histogram based on said address difference; an expected value function calculation means, which calculates expected value function T(f) for function f of an address difference based on said address difference histogram; and a regular patterned defect mix rate calculation means, which calculates mix rate of regular patterned defects included in a defect distribution from said expected value function.